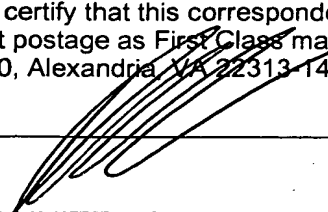


B Image

Docket No.: P2001,0103

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

By:  Date: April 7, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 10/076,977
Applicant : Udo Hartmann
Filed : February 15, 2002
Art Unit : 2829
Examiner : Paresh H. Patel
Title : Test System for Conducting a Function Test of a
Semiconductor Element on a Wafer, and Operating
Method
Docket No. : P2001,0103
Customer No. : 24131

LETTER TO THE OFFICIAL DRAFTSMAN

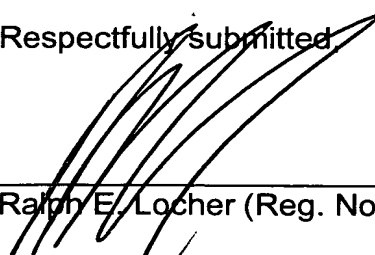
Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450

Sir:

Attached please find one (1) sheet of drawings in the above-identified application.

Please charge any fees due to Deposit Account No. 12-1099 of Lerner and Greenberg, P.A.

Respectfully submitted,


Ralph E. Locher (Reg. No. 41,947)

Date: April 7, 2004

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/av